

Notice of References Cited	Application/Control No. 09/406,663		Applicant(s)/Patent Under Reexamination KNEBEL ET AL.	
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*	B	US-6,483,327	11-2002	Bruce et al.	324/752
*	C	US-5,251,159	10-1993	Rowson, James A.	703/14
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*	E	US-5,270,643	12-1993	Richardson et al.	324/751
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*	W	"The Attack of the "Holey Shmoos": A Case Study of Advanced DFD and Picosecond Imaging Circuit Analysis (PICA)", W. Huott, ITC International Test Conference, IEEE, January 1999
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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*	V	"Picosecond Imaging Circuit Analysis of the POWER3 Clock Distribution", P.N. Sandra, 1999 IEEE International Solid-State Conference, June 1999.
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